

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hideomi Suzawa et al.	
		Filing Date May 11, 2001	Group Art Unit 2812

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Sub-class	Filing Date If Appropriate
AC	AA	US 2002/0006705 A1	01/17/2002	Suzawa et al.			05/10/2001
	AB	4,963,504	10/16/1990	Huang			11/24/1989
	AC	5,182,619	01/26/1993	Pfiester			09/03/1991
	AD	5,185,058	02/09/1993	Cathey, Jr.			01/29/1991
	AE	5,272,100	12/21/1993	Satoh et al.			08/07/1991
	AF	5,302,240	04/12/1994	Hori et al.			02/19/1993
	AG	5,378,309	01/03/1995	Rabinzohn			08/05/1992
	AH	5,543,340	08/06/1996	Lee			12/27/1994
	AI	5,581,092	12/03/1996	Takemura			09/06/1994
	AJ	5,583,067	12/10/1996	Sanchez			02/16/1996
	AK	5,633,738	05/27/1997	Wakui et al.			05/25/1995
	AL	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
	AM	5,767,530	06/16/1998	Ha			09/26/1997
	AN	5,767,930	06/16/1998	Kobayashi et al.			05/20/1997
	AO	5,825,437	10/20/1998	Seo et al.			02/13/1996
	AP	5,828,103	10/27/1998	Hsu			12/26/1995
	AQ	5,841,170	11/24/1998	Adan et al.			01/14/1997
	AR	5,917,199	06/29/1999	Byun et al.			05/15/1998
	AS	5,923,961	07/13/1999	Shibuya et al.			11/12/1997
	AT	5,923,962	07/13/1999	Ohtani et al.			04/28/1995
	AU	5,923,999	07/13/1999	Balasubramanyam et al.			10/29/1996
	AV	6,259,138	07/10/2001	Ohtani et al.			12/16/1999
AC	AW	6,369,410	04/09/2002	Yamazaki et al.			12/15/1998

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
AC	AX	10-233511	09/02/1998	JAPAN			Full

Examiner Signature

Date Considered

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<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hidomi Suzawa et al.	O P E S C MAR 20 2003 P A T E N T & T R A D E M A R K O F F I C E
		Filing Date May 11, 2001	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
AC	AA	5,112,766	05/12/1992	Fujii et al.			07/16/1991
	AB	5,599,741	02/04/1997	Matsumoto et al.			06/07/1995
	AC	5,605,854	02/25/1997	Yoo			02/20/1996
	AD	5,851,885	12/22/1998	Wen			05/30/1997
	AE	5,973,378	10/26/1999	Ohtani			11/24/1997
	AF	6,001,714	12/14/1999	Nakajima et al.			09/26/1997
	AG	6,225,966	05/01/2001	Ohtani et al.			03/23/1998
	AH	6,271,065	08/07/2001	Miyamoto et al.			01/31/2000
	AI	6,323,070	11/27/2001	Yamazaki			09/14/1998
	AJ	6,335,290	01/01/2002	Ishida			03/29/1999
	AK	6,365,917	04/02/2002	Yamazaki			11/16/1999
	AL	US 2001/0041392 A1	11/15/2001	Suzawa et al.			05/11/2001
	AM	US 2001/0052950 A1	12/20/2001	Yamazaki et al.			03/16/2001
	AN	US 2002/0000551 A1	01/03/2002	Yamazaki et al.			03/02/2001
	AO	US 2002/0016028 A1	02/07/2002	Yamazaki et al.			06/05/2001
	AP	US 2001/0041392 A1	11/15/2001	Suzawa et al.			05/11/2001
	AQ	US 2001/0049197 A1	12/06/2001	Yamazaki et al.			06/04/2001
	AR	US 2002/0006705 A1	01/17/2002	Suzawa et al.			05/10/2001

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes      No
AC	AS	WO 87/07079	11/19/1987	WIPO			

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
AC	AT	Hatano et al., "A Novel Self-aligned Gate-overlapped LDD Poly-Si TFT with High Reliability and Performance", IEDM Technical Digest 97, pp. 523-526

Examiner Signature	Date Considered
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

1/09/04